

PRODUCT TECHNICAL BRIEF

KYKY EM-8200 Ultra-High-Resolution Field-Emission SEM

KYKY EM-8200 Ultra-High-Resolution Field-Emission SEM
- LeakLab solutions for leak testing, vacuum systems and test equipment.

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Technical Data

PARAMETER	PUBLISHED VALUE / INFORMATION
SE resolution	0.8 nm at 15 kV; 1.5 nm at 1 kV
Magnification	1×-3,000,000×; optical 1×-100×
Electron source	Schottky field-emission gun
Accelerating voltage	0.2-30 kV
Detectors listed by KYKY	High-vacuum SE, retractable four-segment semiconductor BSE, chamber infrared camera and Inlens
Stage	Five-axis motorized large-specimen stage
Options	EDS, EBSD, STEM, CL, load lock, heating, cooling and tensile stages

Technical and Project Information

Current KYKY field-emission SEM with stage deceleration, low-aberration objective and Inlens detection. Manufacturer specifications list 0.8 nm SE resolution at 15 kV and 1.5 nm at 1 kV.

The EM-8200 is designed for low-voltage, high-resolution imaging in semiconductor, energy-materials and advanced research applications. It combines stage deceleration, a new low-aberration objective and a low-noise Inlens detector.

Confirm installed detectors, analytical ports, stage envelope, site preparation, chilled water or other utilities, vibration and field limits, software licenses and the exact acceptance test.

- Helium Reference Leaks
- Scanning Electron Microscopes
- Leak-Detector Accessories

WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

mail@leaklab.org

Regarding: KYKY EM-8200 Ultra-High-Resolution Field-Emission SEM

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.